



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2829
Examiner: J. Hollington

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In Re NEW PATENT APPLICATION Of:

Applicant: Mikio OHTAKI)
Appln. No.: 09/904,663)
Filed: July 16, 2001)
For: SEMICONDUCTOR DEVICE)
TEST METHOD)
Atty Ref.: KAN 120D1)

September 17, 2002

Commissioner for Patents
Washington, D.C. 20231

Certification Under 37 C.F.R. §1.8 (if applicable)

I hereby certify that this Amendment and Petition for Extension of Time are being deposited with the United States Postal Service as First Class Mail under 37 C.F.R. §1.8 on this **September 17, 2002** and addressed to the Commissioner for Patents, Washington, D.C. 20231.

Steven M. Rabin

Typed or printed name of person
mailing the Amendment and
Petition for Extension of Time

Signature of person mailing the
Amendment and Petition for Extension
of Time

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M. Brunson
10/9/02

In Re NEW PATENT APPLICATION Of:

Applicant: Mikio OHTAKI

Appln. No.: 09/904,663

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TEST METHOD

Atty Ref.: KAN 120D1

AMENDMENT

September 17, 2002

Commissioner for Patents
Washington, D.C. 20231

Sir:

Responsive to the Examiner's Action dated April 17, 2002, a Petition for a Two-Month Extension of Time being submitted herewith, please amend the application as follows:

IN THE CLAIMS

Please cancel claims 28-41, and amend claims 21 and 27 without prejudice and add new claims 42-52, as follows:

--21. (Amended) A method for manufacturing semiconductor devices,
the method comprising:

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